

Notice of References Cited		Application/Control No. 10/807,822	Applicant(s)/Patent Under Reexamination EDWARDS, JATHAN D.	
		Examiner SONYA MAZUMDAR	Art Unit 1791	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0124658	05-2008	Wago, Koichi	430/320
*	B	US-5,142,385	08-1992	Anderson et al.	359/10
*	C	US-4,712,852	12-1987	Funato et al.	359/18
*	D	US-3,560,205	02-1971	Urbach	430/1
*	E	US-4,394,661	07-1983	Peeters, Hugo K.	347/264
*	F	US-6,324,139	11-2001	Nakane, Kazuhiko	369/47.52
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 58094149 A	06-1983	Japan	SAKAI, NOBUHIKO	
	O	JP 01315048 A	12-1989	Japan	SAKAI, NOBUHIKO	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fidler er al. "A Method of Ruling Circular Diffraction Gratings and Their Use in the Moire Technique of Strain Analysis", Journal of Strain Analysis - Vol. I Number 2, 1966, pp.160-164.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.